

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10552494	ST-DENIS, YVES
	Examiner	Art Unit
	Jaisle, Cecilia M	1624

SEARCHED

Class	Subclass	Date	Examiner
514	222.5, 252.04, 255.05, 269	10/19/2007	Cecilia Jaisle
544	8, 238, 279	10/19/2007	Cecilia Jaisle
514	222.5, 252.04, 255.05, 269	5/18/2008	C. Jaisle
544	8, 238, 279	5/18/2008	C. Jaisle

SEARCH NOTES

Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/19/2007	Cecilia Jaisle

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
514	222.5, 252.04, 255.05, 269	5/18/2008	C. Jaisle
544	8, 238, 279	5/18/2008	C. Jaisle